

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

KOYANAGI ET AL.

Examiner

ADAM COONEY

Art Unit

2444

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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